

riscure

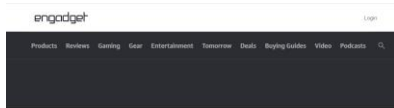
driving your security forward

HARDWARE SHIFT-LEFT

PRE-SILICON FAULT INJECTION
EVALUATION AND POWER SIDE
CHANNEL TESTING

NICOLE FERN

PRODUCTS IN THE WILD CONSTANTLY BEING HACKED USING FI AND SCA



It's already possible to hack an AirTag

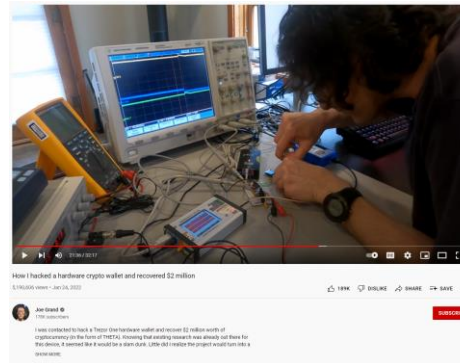
The security risks are small, but there's a lot of potential for enthusiasts.



<https://www.engadget.com/airtag-nfc-hack-205735409.html>



<http://www.ausgamestore.com/xbox-360-slim/matrix-glitcher-slim.html>



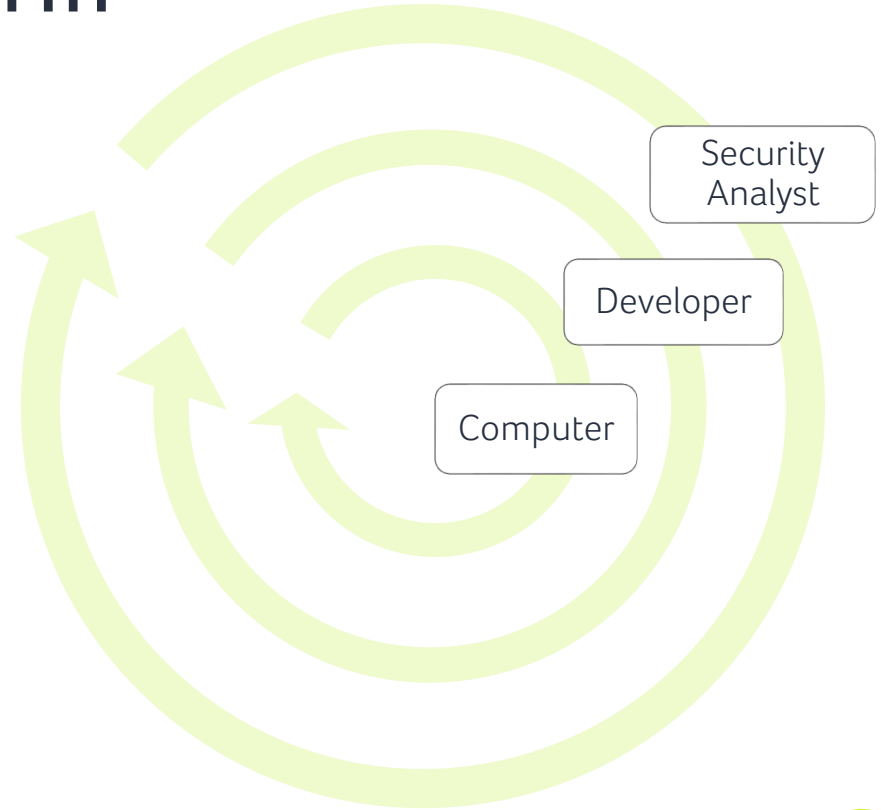
<https://www.youtube.com/watch?v=dT9y-KQbqi4>



<https://www.esat.kuleuven.be/cosic/blog/dismantling-dst80-based-immobiliser-systems/>

SECURITY TOOLING PHILOSOPHY

- Enable codifying of security insights that can integrate into continuous compute loop
- Enable developers/designers to perform security analysis
- An EDA tool with a light salting of security is not a security tool



GOAL OF THIS TALK

- Share our approach to infusing security knowledge into EDA tools and leveraging their best features for pre-silicon SCA/FI analysis
- Show some technical details and case studies behind our pre-silicon offerings
- Show pre-silicon SCA/FI analysis can be used as verification step to **detect** and **mitigate** issues before tapeout
- Show you don't need to be a security expert to find issues
- Gather feedback

PRE-SILICON FAULT INJECTION

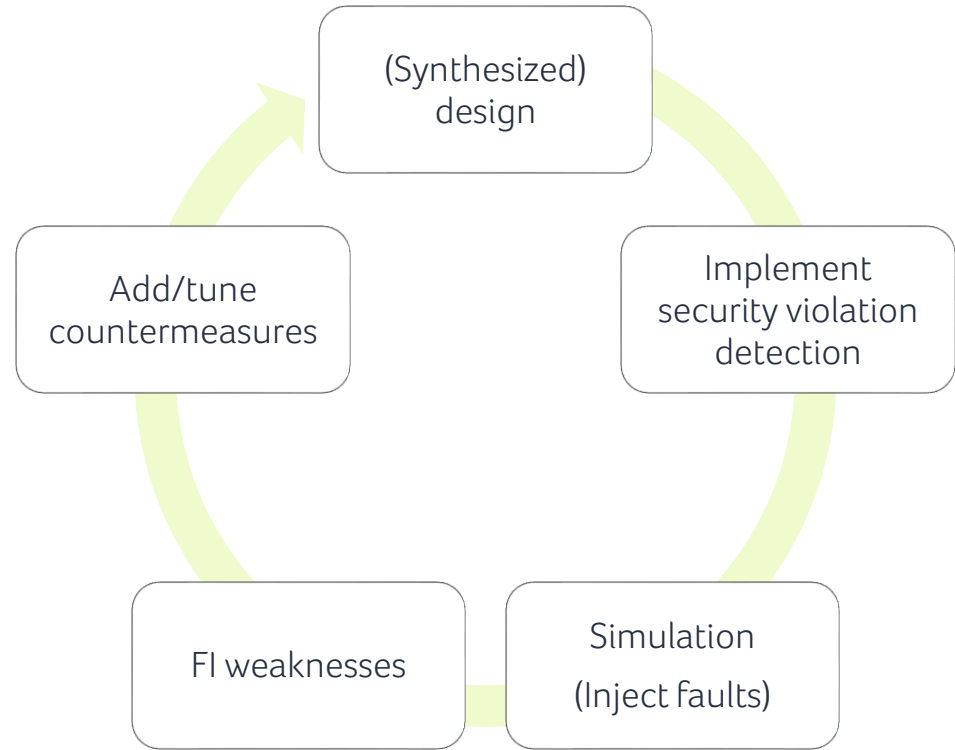
FI SIMULATION

1. Fault Model

- Set of signals and time intervals faults injected during simulation

2. Outcomes

- Classify effects of the fault as security relevant or not
- Threat modelling required to implement **security violation detectors** (“assertions”)



CPU CASE STUDY: PICORV32



Identify sensitive RTL registers

- How can we flip a branch condition?
- Fault Model: single bit flips for all clocks and all registers/wires

```
1 void secureboot(void) {
2     set_test_status(TEST_START);
3     debug("branch test\n");
4
5     set_test_status(TEST_TRIGGER_UP);
6     char success = *(volatile unsigned char *) (UART0_BASE_ADDRESS + UART0_RX_DATA);
7     if(success) {
8         set_test_status(TEST_TRIGGER_DOWN);
9         debug("success\n");
10        set_test_status(TEST_FI_SUCCESS);
11    } else {
12        set_test_status(TEST_TRIGGER_DOWN);
13        debug("failure\n");
14        set_test_status(TEST_FI_FAIL);
15    }
16 }
```

<https://github.com/YosysHQ/picorv32>

RESULTS

- Total faults injected: 1386400
- Exploitable: 408

Glitched Signal Name	Status	PC	Function	Source File
picorv32.instr_rdcycleh	TEST_EXPLOITABLE	00000078	set_test_status	main.c:38
picorv32.instr_rdinstr	TEST_EXPLOITABLE	00000078	set_test_status	main.c:38
picorv32.instr_rdinstrh	TEST_EXPLOITABLE	00000078	set_test_status	main.c:38
picorv32.instr_rdcycleh	TEST_EXPLOITABLE	00000078	set_test_status	main.c:38
picorv32.instr_rdinstr	TEST_EXPLOITABLE	00000078	set_test_status	main.c:38
picorv32.instr_rdinstrh	TEST_EXPLOITABLE	00000078	set_test_status	main.c:38

Vulnerable lines of code highlighted



Software countermeasures



Ranking signals by
vulnerability guides
countermeasure insertion

of exploitable faults

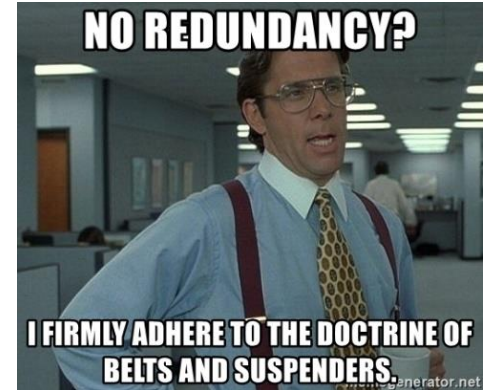


Hardware countermeasures

VERIFYING FI COUNTERMEASURES

- **HW countermeasure:** duplicate program counter and reset core if mismatch
- **SW countermeasure:** implement double check for success condition in software

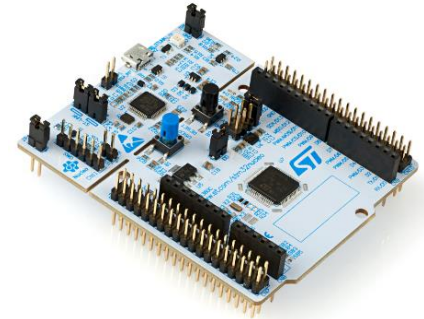
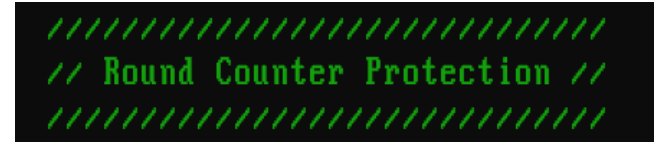
	Vanilla	Harden RTL	Harden SW	Harden RTL + SW
Total	1386400	1540800	1386400	1540800
Exploitable faults	408	358	20	2
Exploitable signals	268	264	4	2
Detections	0	0	376	361



(this experiment is waaay to limited to conclude anything general about hardware vs software countermeasures)

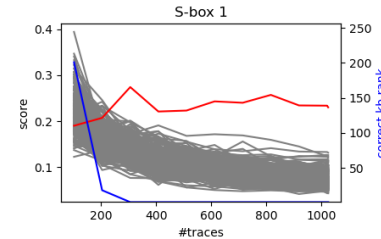
ADDITIONAL CASE STUDIES

- OpenTitan AES round counter protection
 - FI simulation revealed that countermeasures inserted by OpenTitan team were optimized away by synthesis tool
 - Reported to OpenTitan team and they have a fix
 - <https://github.com/lowRISC/opentitan>
- Arm Cortex-M0
 - FI Simulator (netlist) v. EMFI on real device
 - There is a reasonable overlap with post-silicon testing



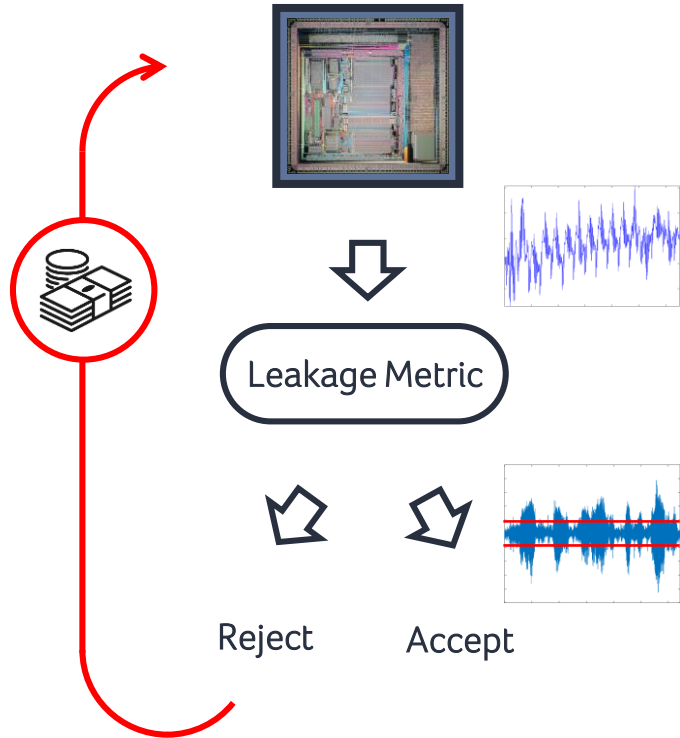
PRE-SILICON SIDE CHANNEL ANALYSIS

SCA SIMULATION: SCATE

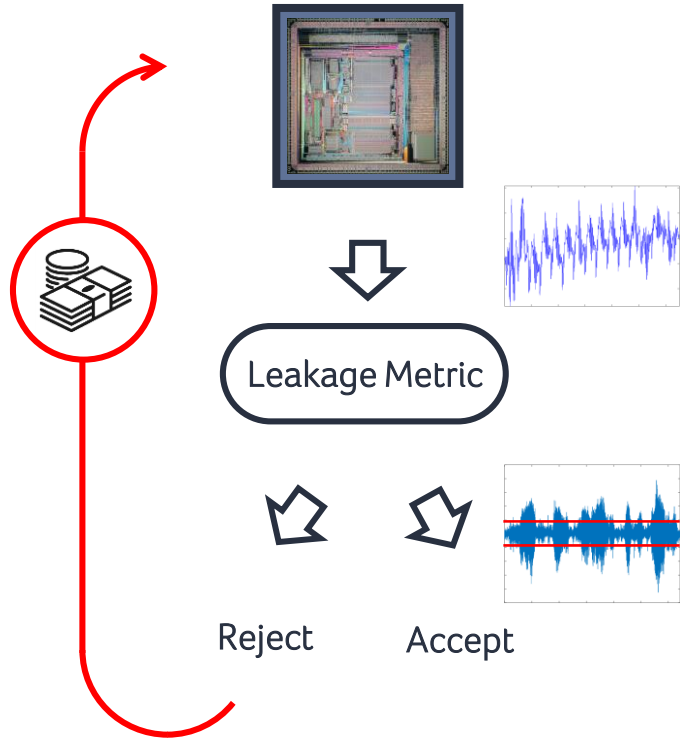


We can simulate traces to obtain
“traditional” CPA plots – noiseless!

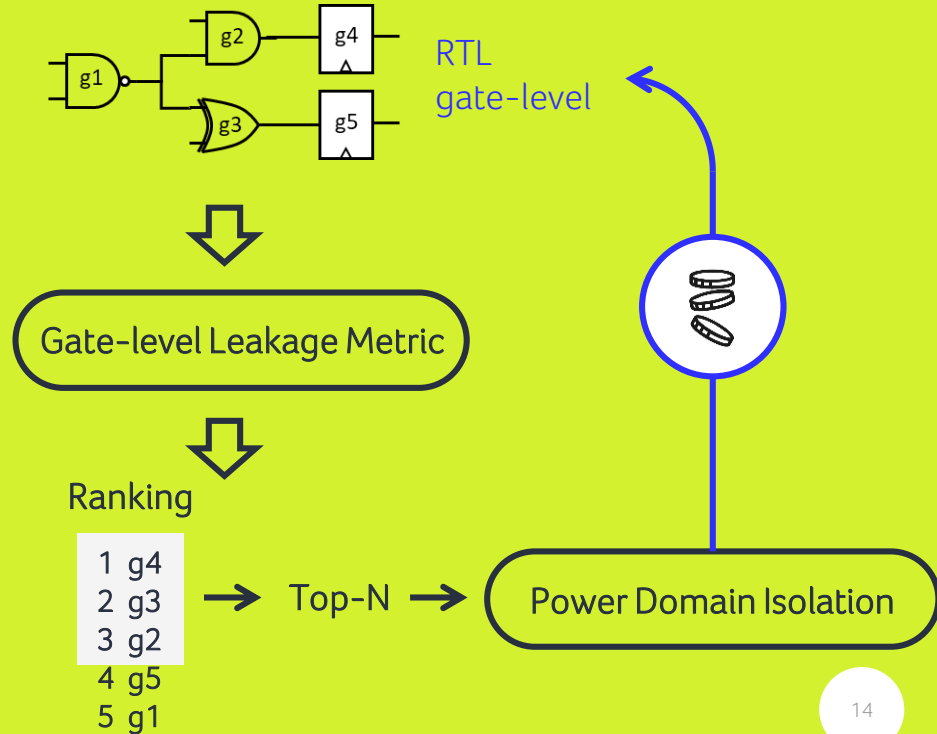
POST-SILICON



POST-SILICON



PRE-SILICON



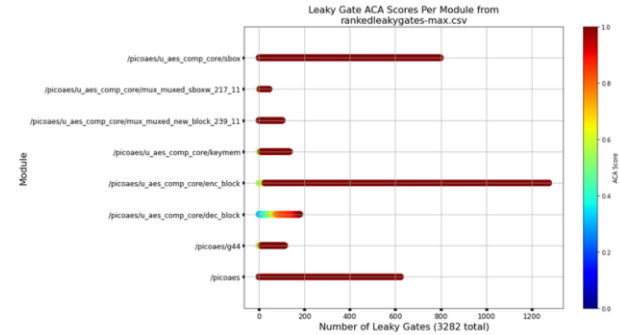
WITH RANKED LEAKY GATE LIST YOU CAN...

- Pinpoint root cause of leakage in design

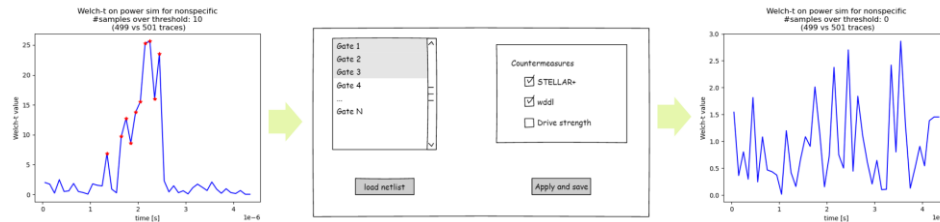
Leaky gate	Source line
/picoaes/g88411	../../rtl/picoaes/aes_comp_decipher_block.v 337 19
/picoaes/g88412	../../rtl/picoaes/aes_comp_decipher_block.v 337 19
/picoaes/g88421	../../rtl/picoaes/aes_comp_encipher_block.v 153 26
/picoaes/g129279	../../rtl/picoaes/aes_comp_encipher_block.v 153 26
/picoaes/g129444	../../rtl/picoaes/aes_comp_encipher_block.v 153 26
/picoaes/g129741	../../rtl/picoaes/aes_comp_encipher_block.v 153 26


```

151 function [127 : 0] addroundkey(input [127 : 0] data, input [127 : 0] rkey);
152   begin
153     addroundkey = data ^ rkey;
154   end
155 endfunction // addroundkey
    
```

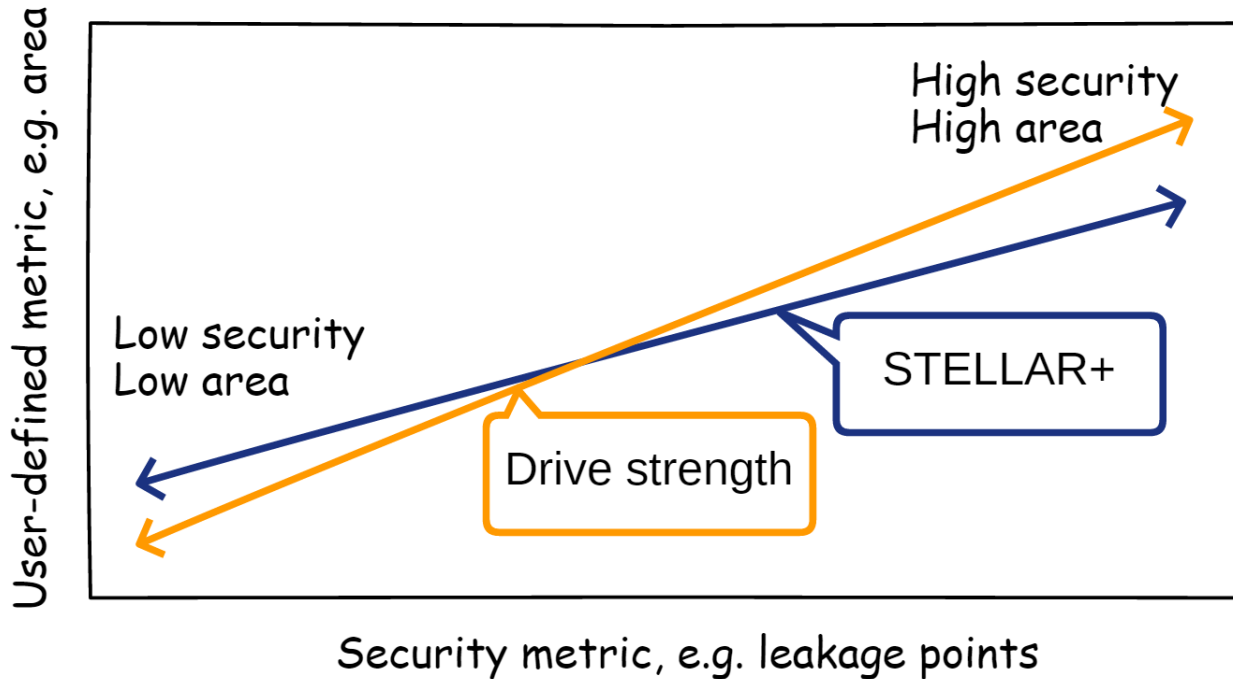


- Begin to automate countermeasure insertion (future work)



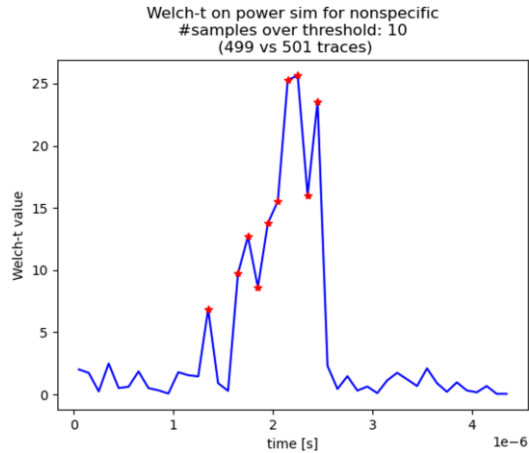
DESIGN SPACE EXPLORATION

For top N leaky gates gates, trade off security / user defined function / countermeasure



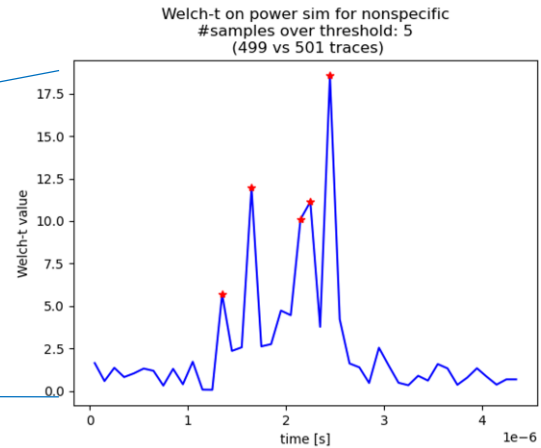
CASE STUDY: MASKED AES DESIGN

No masking



$$X \rightarrow Y$$

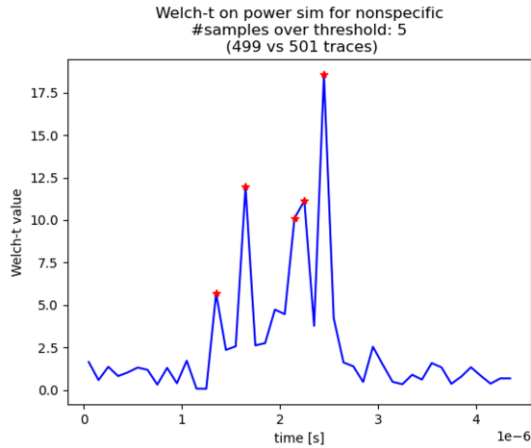
With masking



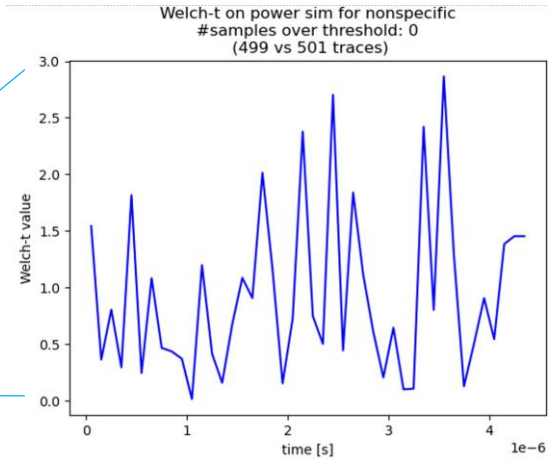
$$X \oplus m_1 \rightarrow Y \oplus m_2$$
$$((X \oplus m_1) \oplus m_1) \oplus m_2 \rightarrow Y \oplus m_2$$

CASE STUDY: MASKED AES DESIGN

Masking – unconstrained synthesis



Masking – constrained synthesis



$$x \oplus m_1 \rightarrow y \oplus m_2$$

$$((x \oplus m_1) \oplus m_1) \oplus m_2 \rightarrow y \oplus m_2$$

$$x \oplus m_1 \rightarrow y \oplus m_2$$

$$((x \oplus m_1) \oplus m_2) \oplus m_1 \rightarrow y \oplus m_2$$

KEY TAKEAWAYS



“With post-silicon we can fix the next chip, with pre-silicon we can fix the current chip.”

– Customer Quote

We are:

Enabling **non-security-expert** designers to **root cause** security issues

Enabling continuous integration of insight and experience from security experts into the tooling

Reducing the need for **time consuming / expensive** post-silicon testing

Reducing the **risk** of post-silicon **certification failure** and **insecure** products

“Good security tools find potential vulnerabilities. Great security tools find practical vulnerabilities.”

– Jasper Van Woudenberg
(CTO, Riscure North America)

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driving your security forward

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